

# INTERNATIONAL STANDARD

# IEC 61000-4-6

Second edition  
2003-05

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BASIC EMC PUBLICATION

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## Electromagnetic compatibility (EMC) –

### Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

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## CONTENTS

FOREWORD .....	7
INTRODUCTION .....	11
1 Scope and object .....	13
2 Normative references .....	13
3 Definitions .....	13
4 General .....	17
5 Test levels .....	19
6 Test equipment .....	19
6.1 Test generator .....	19
6.2 Coupling and decoupling devices .....	21
6.3 Verification of the common mode impedance at the EUT port of coupling and decoupling devices .....	27
6.4 Setting of the test generator .....	29
7 Test set-up for table-top and floor-standing equipment .....	31
7.1 Rules for selecting injection methods and test points .....	31
7.2 Procedure for CDN injection application .....	35
7.3 Procedure for clamp injection when the common-mode impedance requirements can be met .....	35
7.4 Procedure for clamp injection when the common-mode impedance requirements cannot be met .....	37
7.5 Procedure for direct injection .....	37
7.6 EUT comprising a single unit .....	39
7.7 EUT comprising several units .....	39
8 Test procedure .....	39
9 Evaluation of the test results .....	41
10 Test report .....	43
Annex A (normative) Additional information regarding clamp injection .....	67
Annex B (informative) Selection criteria for the frequency range of application .....	77
Annex C (informative) Guide for selecting test levels .....	81
Annex D (informative) Information on coupling and decoupling networks .....	83
Annex E (informative) Information for the test generator specification .....	91
Figure 1 – Rules for selecting the injection method .....	33
Figure 2 – Immunity test to RF conducted disturbances .....	47
Figure 3 – Test generator set-up .....	49
Figure 4 – Definition of the wave shapes occurring at the output of the EUT port of a coupling device (e.m.f. of test level 1) .....	49
Figure 5 – Principle of coupling and decoupling .....	55
Figure 6 – Principle of coupling and decoupling according to the clamp injection method .....	55
Figure 7 – Details of set-ups and components to verify the essential characteristics of coupling and decoupling devices and the 150 Ω to 50 Ω adapters .....	59

Figure 8 – Set-up for level setting (see 6.4.1).....	61
Figure 9 – Example of test set-up with a single unit system.....	63
Figure 10 – Example of a test set-up with a multi-unit system.....	65
Figure A.1 – Circuit for level setting set-up in a 50 Ω test Jig.....	69
Figure A.2 – The 50 Ω test jig construction .....	69
Figure A.3 – Construction details of the EM clamp .....	71
Figure A.4 – Concept of the EM clamp (electromagnetic clamp).....	73
Figure A.5 – Coupling factor of the EM clamp .....	73
Figure A.6 – General principle of a test set-up using Injection clamps .....	75
Figure A.7 – Example of the test unit locations on the ground plane when using injection clamps (top view) .....	75
Figure B.1 – Start frequency as function of cable length and equipment size .....	79
Figure D.1 – Example of a simplified diagram for the circuit of CDN-S1 used with screened cables (see 6.2.1).....	85
Figure D.2 – Example of simplified diagram for the circuit of CDN-M1/-M2/-M3 used with unscreened supply (mains) lines (see 6.2.2.1) .....	85
Figure D.3 – Example of a simplified diagram for the circuit of CDN-AF2 used with unscreened non-balanced lines (see 6.2.2.3).....	87
Figure D.4 – Example of a simplified diagram for the circuit of a CDN-T2, used with an unscreened balanced pair (see 6.2.2.2).....	87
Figure D.5 – Example of a simplified diagram of the circuit of a CDN-T4 used with unscreened balanced pairs (see 6.2.2.2) .....	89
Figure D.6 – Example of a simplified diagram of the circuit of a CDN-T8 used with unscreened balanced pairs (see 6.2.2.2) .....	89
Table 1 – Test levels .....	19
Table 2 – Characteristics of the test generator .....	21
Table 3 – Main parameter of the combination of the coupling and decoupling device .....	21
Table B.1 – Main parameter of the combination of the coupling and decoupling device when the frequency range of test is extended above 80 MHz.....	77
Table E.1 – Required power amplifier output power to obtain a test level of 10 V.....	91

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

**ELECTROMAGNETIC COMPATIBILITY (EMC) –****Part 4-6: Testing and measurement techniques –  
Immunity to conducted disturbances,  
induced by radio-frequency fields**

## FOREWORD

- 1) The IEC (International Electrotechnical Commission) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of the IEC is to promote international cooperation on all questions concerning standardisation in the electrical and electronic fields. To this end and in addition to other activities, the IEC publishes International Standards. Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. The IEC collaborates closely with the International Standardization Organization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of the IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested National Committees.
- 3) The documents produced have the form of recommendations for international use published in the form of standards, technical specifications, technical reports or guides and they are accepted by the National Committees in that sense.
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- 6) Attention is drawn to the possibility that some of the elements of this International Standard may be the subject of patent rights. The IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 61000-4-6 has been prepared by subcommittee 77B: High-frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

This standard forms part 4-6 of IEC 61000. It has the status of a basic EMC publication in accordance with IEC Guide 107, *Electromagnetic compatibility – Guide to the drafting of electromagnetic compatibility publications*.

This second edition cancels and replaces the first edition published in 1996 and its amendment 1 (2000), and constitutes a technical revision.

The text of this standard is based on the following documents:

FDIS	Report on voting
77B/377/FDIS	77B/384/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendment will remain unchanged until 2006. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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## INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

### **Part 1: General**

General considerations (introduction, fundamental principles)

Definitions, terminology

### **Part 2: Environment**

Description of the environment

Classification of the environment

Compatibility levels

### **Part 3: Limits**

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

### **Part 4: Testing and measurement techniques**

Measurement techniques

Testing techniques

### **Part 5: Installation and mitigation guidelines**

Installation guidelines

Mitigation methods and devices

### **Part 6: Generic standards**

### **Part 9: Miscellaneous**

Each part is further subdivided into several parts, published either as international standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example : 61000-6-1).

This part is an international standard which gives immunity requirements and test procedure related to conducted disturbances induced by radio-frequency fields.



## ELECTROMAGNETIC COMPATIBILITY (EMC) –

### Part 4-6: Testing and measurement techniques – Immunity to conducted disturbances, induced by radio-frequency fields

#### 1 Scope and object

This part of IEC 61000-4 relates to the conducted immunity requirements of electrical and electronic equipment to electromagnetic disturbances coming from intended radio-frequency (RF) transmitters in the frequency range 9 kHz up to 80 MHz. Equipment not having at least one conducting cable (such as mains supply, signal line or earth connection) which can couple the equipment to the disturbing RF fields is excluded.

NOTE 1 Test methods are defined in this part for measuring the effect that conducted disturbing signals, induced by electromagnetic radiation, have on the equipment concerned. The simulation and measurement of these conducted disturbances are not adequately exact for the quantitative determination of effects. The test methods defined are structured for the primary objective of establishing adequate repeatability of results at various facilities for quantitative analysis of effects.

The object of this standard is to establish a common reference for evaluating the functional immunity of electrical and electronic equipment when subjected to conducted disturbances induced by radio-frequency fields. The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of an equipment or system against a defined phenomenon.

NOTE 2 As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and if applied, they are responsible for determining the appropriate test levels and performance criteria. TC 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050(161), *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

#### 3 Definitions

For the purpose of this part of IEC 61000, the definitions given in IEC 60050(161) as well as the following definitions apply.

##### 3.1 artificial hand

electrical network simulating the impedance of the human body under average operational conditions between a hand-held electrical appliance and earth

[IEV 161-04-27]

NOTE The construction should be in accordance with CISPR 16-1.

### 3.2

#### **auxiliary equipment**

##### **AE**

equipment necessary to provide the equipment under test (EUT) with the signals required for normal operation and equipment to verify the performance of the EUT

### 3.3

#### **clamp injection**

clamp injection is obtained by means of a clamp-on “current” injecting device on the cable:

- **current clamp**: a transformer, the secondary winding of which consists of the cable into which the injection is made;
- **electromagnetic clamp** (EM clamp): injection device with combined capacitive and inductive coupling

### 3.4

#### **common-mode impedance**

ratio of the common mode voltage and the common-mode current at a certain port

NOTE This common mode impedance can be determined by applying a unity common mode voltage between the terminal(s) or screen of that port and a reference plane (point). The resulting common mode current is then measured as the vectorial sum of all currents flowing through these terminal(s) or screen (see also Figures 8a and 8b).

### 3.5

#### **coupling factor**

ratio given by the open-circuit voltage (e.m.f.) obtained at the EUT port of the coupling (and decoupling) device divided by the open-circuit voltage obtained at the output of the test generator

### 3.6

#### **coupling network**

electrical circuit for transferring energy from one circuit to another with a defined impedance

NOTE Coupling and decoupling devices can be integrated into one box (coupling and decoupling network (CDN)) or they can be in separate networks.

### 3.7

#### **coupling/decoupling network**

##### **CDN**

electrical circuit incorporating the functions of both the coupling and decoupling networks

### 3.8

#### **decoupling network**

electrical circuit for preventing test signals applied to the EUT from affecting other devices, equipment or systems that are not under test

### 3.9

#### **test generator**

generator (RF generator, modulation source, attenuators, broadband power amplifier and filters) capable of generating the required test signal (see Figure 3)

**3.10****electromotive force****e.m.f.**

voltage at the terminals of the ideal voltage source in the representation of an active element  
[IEV 131-01-38:1978]

**3.11****measurement result** **$U_{mr}$** 

voltage reading of the measurement equipment

**3.12****voltage standing wave ratio****VSWR**

ratio of a maximum to an adjacent minimum voltage magnitude along the line

**4 General**

The source of disturbance covered by this part of IEC 61000 is basically an electromagnetic field, coming from intended RF transmitters, that may act on the whole length of cables connected to installed equipment. The dimensions of the disturbed equipment, mostly a sub-part of a larger system, are assumed to be small compared with the wavelengths involved. The in-going and outgoing leads (e.g. mains, communication lines, interface cables) behave as passive receiving antenna networks because of their length, which can be several wavelengths.

Between those cable networks, the susceptible equipment is exposed to currents flowing "through" the equipment. Cable systems connected to an equipment are assumed to be in resonant mode ( $\lambda/4$ ,  $\lambda/2$  open or folded dipoles) and as such are represented by coupling and decoupling devices having a common-mode impedance of 150  $\Omega$  with respect to a ground reference plane. Where possible the EUT is tested by connecting it between two 150  $\Omega$  common-mode impedance connections: one providing an RF source and the other providing a return path for the current.

This test method subjects the EUT to a source of disturbance comprising electric and magnetic fields, simulating those coming from intentional RF transmitters. These disturbing fields (E and H) are approximated by the electric and magnetic near-fields resulting from the voltages and currents caused by the test set-up as shown in Figure 2a.

The use of coupling and decoupling devices to apply the disturbing signal to one cable at the time, while keeping all other cables non-excited, see Figure 2b, can only approximate the real situation where disturbing sources act on all cables simultaneously, with a range of different amplitudes and phases.

Coupling and decoupling devices are defined by their characteristics given in 6.2. Any coupling and decoupling device fulfilling these characteristics can be used. The coupling and decoupling networks in Annex D are only examples of commercially available networks.

## 5 Test levels

No tests are required for induced disturbances caused by electromagnetic fields coming from intentional RF transmitters in the frequency range 9 kHz to 150 kHz.

**Table 1 – Test levels**

Frequency range 150 kHz – 80 MHz		
Level	Voltage level (e.m.f.)	
	$U_0$ dB( $\mu$ V)	$U_0$ V
1	120	1
2	130	3
3	140	10
X <sup>a</sup>	Special	
<sup>a</sup> X is an open level.		

The open-circuit test levels (e.m.f.) of the unmodulated disturbing signal, expressed in r.m.s., are given in Table 1. The test levels are set at the EUT port of the coupling devices, see 6.4.1. For testing of equipment, this signal is 80 % amplitude modulated with a 1 kHz sine wave to simulate actual threats. The effective amplitude modulation is shown in Figure 4. Guidance for selecting test levels is given in Annex C.

NOTE 1 IEC 61000-4-3 also defines test methods for establishing the immunity of electrical and electronic equipment against radiated electromagnetic energy. It covers frequencies above 80 MHz. Product committees may decide to choose a lower or higher transition frequency than 80 MHz (see Annex B).

NOTE 2 Product committees may select alternative modulation schemes.

## 6 Test equipment

### 6.1 Test generator

The test generator includes all equipment and components for supplying the input port of each coupling device with the disturbing signal at the required signal level at the required point. A typical arrangement comprises the following items which may be separate or integrated into one or more test instruments (see 3.9 and Figure 3):

- RF generator(s), G1, capable of covering the frequency band of interest and of being amplitude modulated by a 1 kHz sine wave with a modulation depth of 80 %. They shall have manual control (e.g., frequency, amplitude, modulation index) or in the case of RF synthesizers, they shall be programmable with frequency-dependent step sizes and dwell times;
- attenuator, T1, (typically 0 dB ... 40 dB) of adequate frequency rating to control the disturbing test source output level. T1 may be included in the RF generator and is optional;
- RF switch, S1, by which the disturbing test signal can be switched on and off when measuring the immunity of the EUT. S1 may be included in the RF generator and is optional;
- broadband power amplifier(s), PA, may be necessary to amplify the signal if the output power of the RF generator is insufficient;

- low-pass filters (LPF), and/or high-pass filters (HPF) may be necessary to avoid interference caused by (higher order or sub-) harmonics with some types of EUT, for example RF receivers. When required they shall be inserted in between the broadband power amplifier, PA, and the attenuator T2;
- attenuator, T2, (fixed  $\geq 6$  dB,  $Z_o = 50 \Omega$ ), with sufficient power ratings. T2 is provided to reduce the mismatch from the power amplifier to the network.

NOTE T2 may be included in a coupling and decoupling network and can be left out if the output impedance of the broadband power amplifier remains within the specification under any load condition.

Characteristics of the test generator with and without modulation are given in Table 2.

**Table 2 – Characteristics of the test generator**

<b>Output impedance</b>	50 $\Omega$
<b>Harmonics and distortion</b>	any spurious spectral line shall be at least 15 dB below the carrier level
<b>Amplitude modulation</b>	internal or external, 80 % $\pm$ 5 % in depth 1 kHz $\pm$ 10 % sine wave
<b>Output level</b>	sufficiently high to cover test level (see also Annex E)

## 6.2 Coupling and decoupling devices

Coupling and decoupling devices shall be used for appropriate coupling of the disturbing signal (over the entire frequency range, with a defined common-mode impedance at the EUT port) to the various cables connected to the EUT and for preventing applied test signals from affecting other devices, equipment and systems that are not under test.

The coupling and decoupling devices can be combined into one box (a coupling/ decoupling network, CDN) or can consist of several parts. The main coupling and decoupling device parameter, the common-mode impedance seen at the EUT-port, is specified in Table 3.

The preferred coupling and decoupling devices are the CDNs, for reasons of test reproducibility and protection of the AE. However, if they are not suitable or available, other injection methods can be used. Rules for selecting the appropriate injection method are given below and in 7.1.

**Table 3 – Main parameter of the combination of the coupling and decoupling device**

Parameter	Frequency band	
	0,15 MHz – 26 MHz	26 MHz – 80 MHz
$ Z_{ce} $	150 $\Omega \pm 20 \Omega$	150 $\Omega + 60 \Omega - 45 \Omega$

NOTE 1 Neither the argument of  $Z_{ce}$  nor the decoupling factor between the EUT port and the AE port are specified separately. These factors are embodied in the requirement that the tolerance of  $|Z_{ce}|$  shall be met with the AE-port open or short-circuited to the ground reference plane.

NOTE 2 When clamp injection methods are used, without complying with the common-mode impedance requirements for the auxiliary equipment, the requirements of  $Z_{ce}$  may not be met. However, the injection clamps can provide acceptable test results when the guidance of 7.4 is followed.

### 6.2.1 Coupling/decoupling networks (CDNs)

These networks comprise the coupling and decoupling circuits in one box and can be used for specific unscreened cables e.g. CDN-M1, CDN-M2, CDN-M3, CDN-T2, CDN-T4, CDN-AF-2, see Annex D. Typical concepts of the coupling and the decoupling networks are given in Figures 5c and 5d. The networks shall not unduly affect the functional signals. Constraints on such effects may be specified in the product standards.

#### 6.2.1.1 CDNs for power supply lines

Coupling/decoupling networks are recommended for all power supply connections. However, for high power (current  $\geq 16$  A) and/or complex supply systems (multi-phase or various parallel supply voltages) other injection methods may be selected.

The disturbing signal shall be coupled to the supply lines, using type CDN-M1 (single wire), CDN-M2 (two wires) or CDN-M3 (three wires), or equivalent networks (see Annex D). Similar networks can be defined for a 3-phase mains system. The coupling circuit is given in Figure 5c.

The performance of the CDN shall not be unduly degraded by saturation of the magnetic material due to current taken by the EUT. Wherever possible, the network construction should ensure that the magnetising effect of the forward current is cancelled by that due to the return current.

If in real installations the supply wires are individually routed, separate CDN-M1 coupling and decoupling networks shall be used and all input ports shall be treated separately.

If the EUT is provided with other earth terminals (e.g. for RF purposes or high leakage currents), they shall be connected to the ground reference plane:

- through the CDN-M1 when the characteristics or specification of the EUT permit. In this case, the (power) supply shall be provided through the CDN-M3 network;
- when the characteristics or specification of the EUT do not permit the presence of a CDN-M1 network in series with the earth terminal for RF or other reasons, the earth terminal shall be directly connected to the ground reference plane. In this case the CDN-M3 network shall be replaced by a CDN-M2 network to prevent an RF short circuit by the protective earth conductor. When the equipment was already supplied via CDN-M1 or CDN-M2 networks, these shall remain in operation.

**Warning:** The capacitors used within the CDNs bridge live parts. As a result, high leakage currents may occur and safety connections from the CDN to the ground reference plane are obligatory (in some cases, these connections may be provided by the construction of the CDN).

#### 6.2.1.2 CDNs for unscreened balanced lines

For coupling and decoupling disturbing signals to an unscreened cable with balanced lines, a CDN-T2, CDN-T4 or CDN-T8 shall be used as coupling and decoupling network. Figures D.4, D.5 and D.6 in Annex D show these possibilities:

- CDN-T2 for a cable with 1 symmetrical pair (2 wires);
- CDN-T4 for a cable with 2 symmetrical pairs (4 wires);
- CDN-T8 for a cable with 4 symmetrical pairs (8 wires).